Search Notes

Application/Control No.	Applicant(s)/l Reexamination

10/564,034

Examiner

Hau V. Phan

Applicant(s)/Patent under Reexamination MIYAGAWA ET AL. Art Unit

3618

SEARCHED				
Class	Subclass	Date	Examiner	
180	291 274 297 784	10/29/2007	HP	
	300			
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248	605	10/29/2007	HP	
	562			
	634	· "		
267	140.3	10/29/2007	HP	
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296	187.09	10/29/2007	HP	

INTERFERENCE SEARCHED				
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